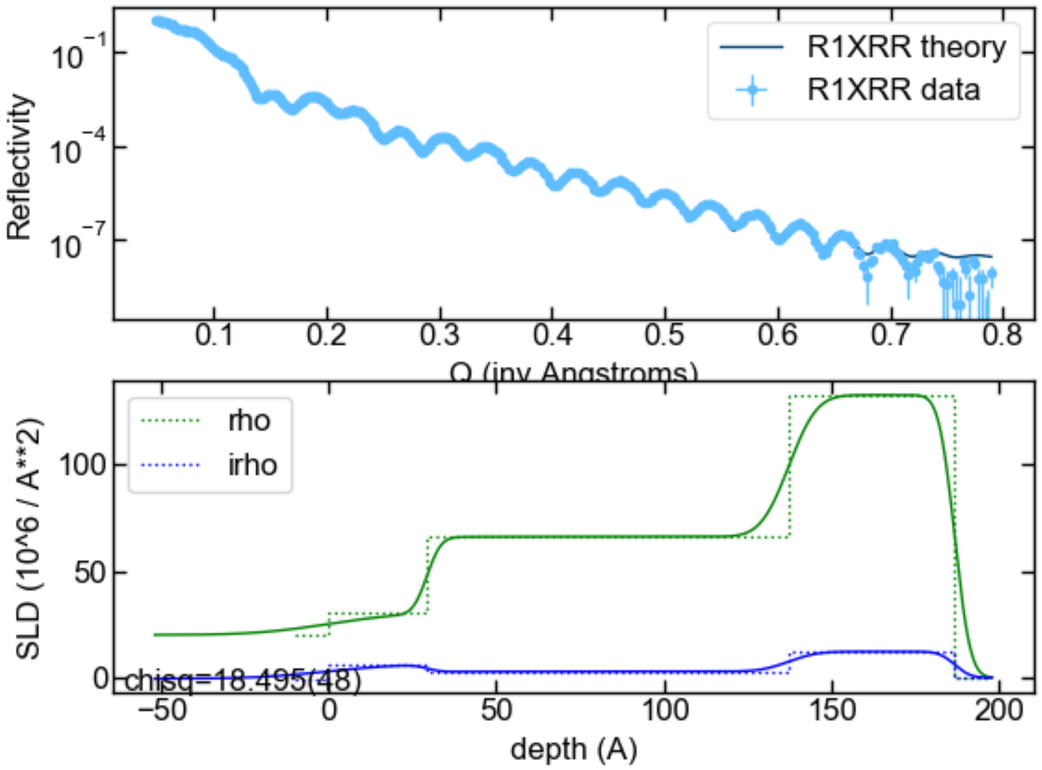
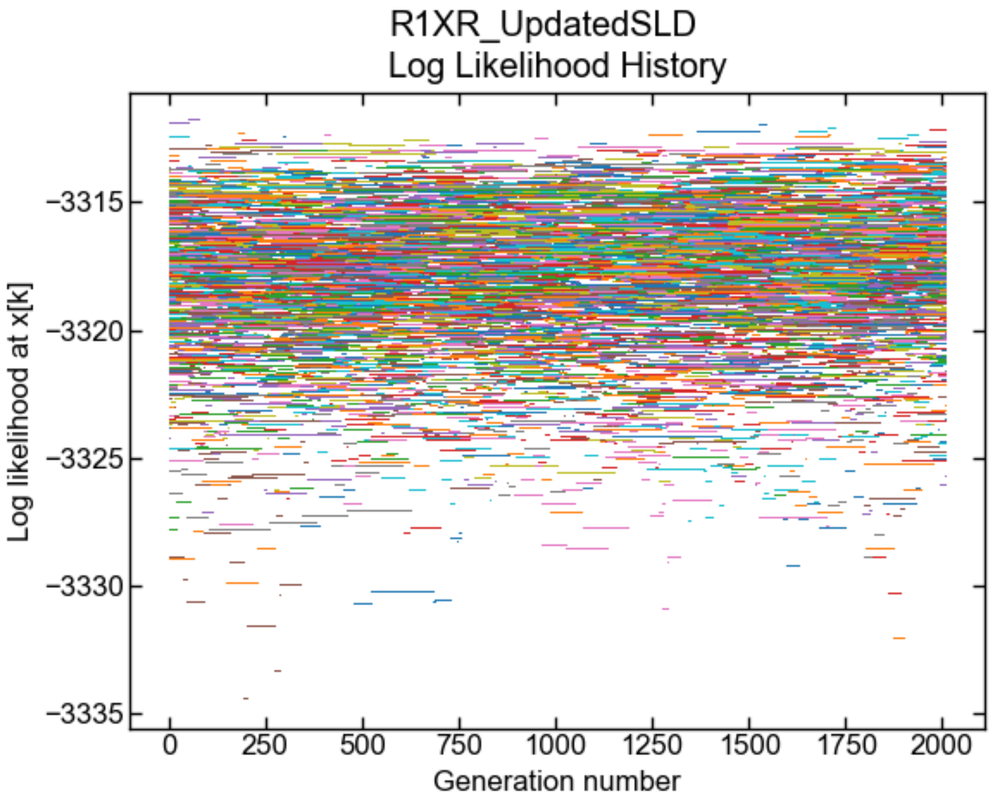
X-ray Reflectivity Best Fit: 5-Layer Box Model

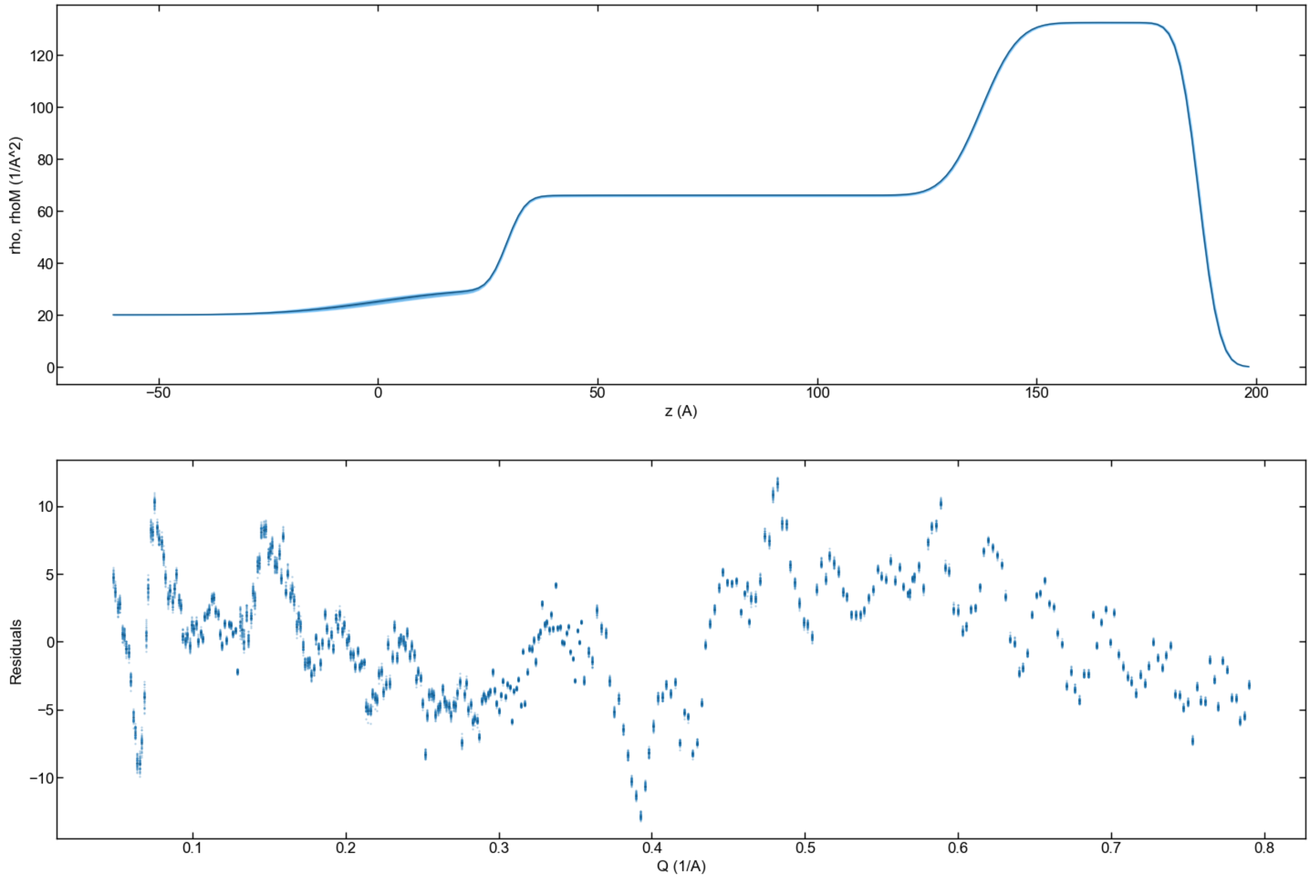


Parameter	Silicon	Oxide	Permalloy	Platinum	Air
roughness, σ (Å)	17.33	3.322	6.603	3.711	0.0
incoherent SLD, ρ_i (× 10–6 Å–2)	–0.458	6.436	2.904	12.24	0.0
SLD, ρ (× 10^{-6} $Å^{-2}$)	20.07	30.37	66.07	132.5	0.0
thickness, t (Å)	0.0	29.32	108.1	49.54	0.0

Simple box model composed of five layers:
silicon, oxide, permalloy, platinum, and air
All parameters in the silicon and air layers were fixed to *a priori* value (except for silicon roughness)
SLD of oxide layer is much greater than the nominal value, which we take to mean that there is some alloy due to the permalloy
Measured Value: 30.37 × 10^{-6} $Å^{-2}$
Nominal Value: 17.7 × 10^{-6} $Å^{-2}$
Thicknesses and surface roughnesses for the permalloy and platinum layers are very similar to the values measured in the neutron fits

X-ray Reflectivity Best Fit: Convergence and Model Uncertainty





X-ray Reflectivity Best Fit: Variance and Correlations